



中国认可
国际互认
检测
TESTING
CNAS L12524

Test Report

Sample Name: The integrated circuit

Part Number: SN65LVDS1DBVR

Manufacturer: TI

Customer:

Shenzhen Chuangxin Online Testing Service Co., Ltd.

December 01, 2025



Test Report

Customer:

Customer Address:

Sample Name: The integrated circuit

Part Number: SN65LVDS1DBVR

Manufacturer: TI

Date Code: 2515

Package Type: SOT-23-5

Quantity Received: 6000 PCS

Quantity Inspected: 10 PCS

Date Received: 11/27/2025

Date Tested: 11/27/2025/15: 00 - 12/01/2025/16: 00

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Tested by _____

Issued by

Inspected by _____

(Stamp)

Approved by _____

Test Items And Conclusions

Results Analysis			Conclusion
According to the requirements of the client, 10 samples were subjected to three types of inspections: External visual inspection, Radiography(X-ray), Internal visual inspection. None of the three inspections revealed any standard defects.			✓
Test Items	Quantity (PCS)	Test Standard	Result
<input checked="" type="checkbox"/> Documentation and Packaging inspection	6000	SAE AS6171/2A-2017	✓
<input checked="" type="checkbox"/> External visual inspection	10	SAE AS6171/2A-2017	✓
<input type="checkbox"/> Top permanency test	N/A	N/A	N/A
<input checked="" type="checkbox"/> Radiography(X-ray)	5	SAE AS6171/5-2022	✓
<input type="checkbox"/> XRF test	N/A	N/A	N/A
<input type="checkbox"/> Pin correlation test	N/A	N/A	N/A
<input type="checkbox"/> Key functional test(KFT)	N/A	N/A	N/A
<input type="checkbox"/> SAT test	N/A	N/A	N/A
<input type="checkbox"/> Solderability Analysis	N/A	N/A	N/A
<input type="checkbox"/> Reflow soldering	N/A	N/A	N/A
<input checked="" type="checkbox"/> Internal visual inspection	1	SAE AS6171/4-2016	✓

Result Status: ✓ Acceptable ✗ Nonconforming ● Suspicious N/A Not tested & not applicable



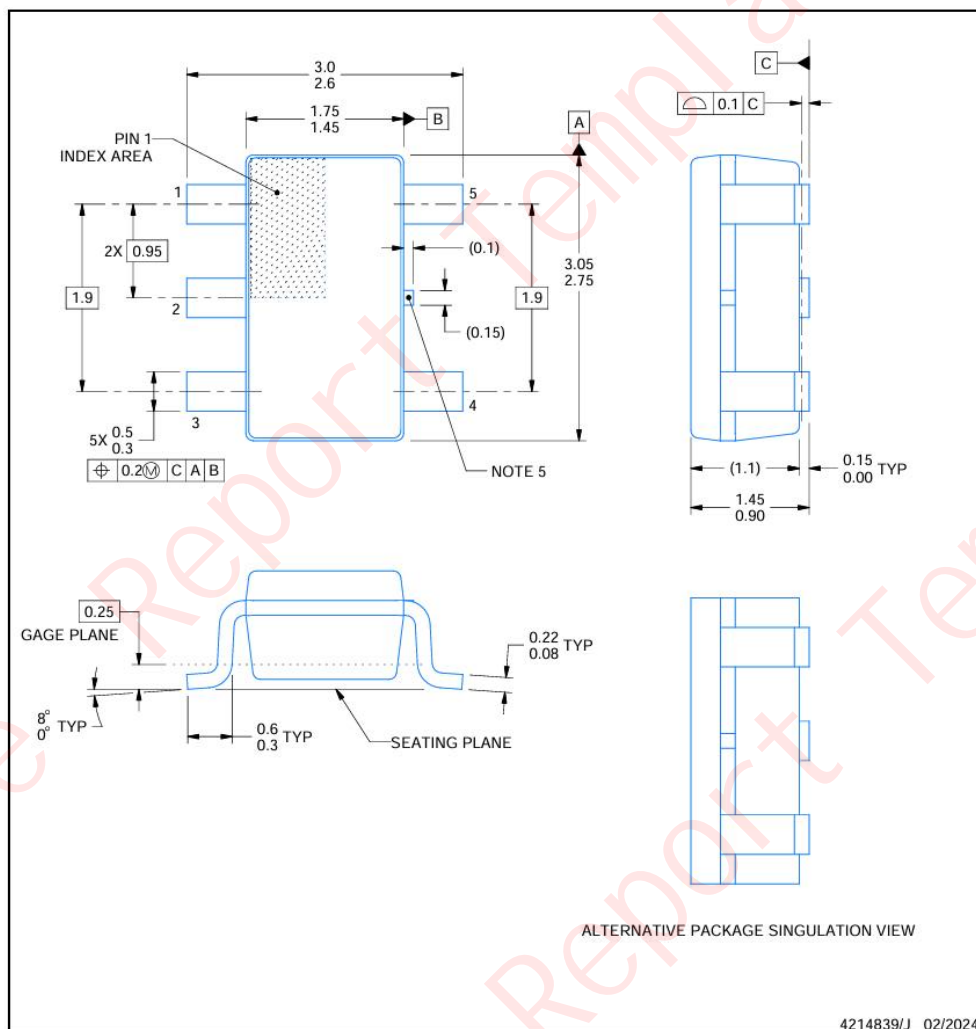
Test Equipment

Device name	Serial No.	Model No.	Calibration Due Date
Optical microscope	TC-S-WG-007	SEZ-260	2026/07/07
Digital caliper	TC-S-WG-002	(0~150) mm	2026/07/07
X-ray flaw detector	TC-S-WS-001	X6600	N/A
Metalloscope	TC-S-HX-004	FJ-5A	2026/07/07
Laser lid opener	TC-S-HX-009	DM300-IC	N/A
Datasheet Reference 《TI SN65LVDS1DBVR》:			
https://erp.iclab-cn.com/erp/pdfdata.php?spm=M01oUDZCMitTUjBhVVJpQ3AwR2QrcDQxbi9ucFFzRklUSnFBeWticTJFZmNyZzZtY0dRdUY4b2M4Rk5oWThhOVZ6ZndLNU1GY3hMcDFqMXErM1p1djREVUM0bkdzS0VmSjBseFNscTR1alU9			

1. Device description:

The SN65LVDS1, SN65LVDS2, and SN65LVDT2 devices are single, low-voltage, differential line drivers and receivers in the small-outline transistor package. The outputs comply with the TIA/EIA-644 standard and provide a minimum differential output voltage magnitude of 247 mV into a 100-Ω load at signaling rates up to 630 Mbps for drivers and 400 Mbps for receivers.

2. Package dimensions:



3. Documentation and Packaging inspection:

Outer Box	1	Outer Box Size (cm)	N/A
Inner Box	2	Inner Box Size (cm)	N/A
Total Weight	330 g	Date Code	2515
COO	N/A	Material Number	N/A
Quantity Received	6000 PCS	Quantity Inspected	10 PCS
Moisture Protection	N/A	ESD Protection	N/A
Sample No (Date Code + Serial No)	2515-#1~#10		

Received view-1



Received view-2



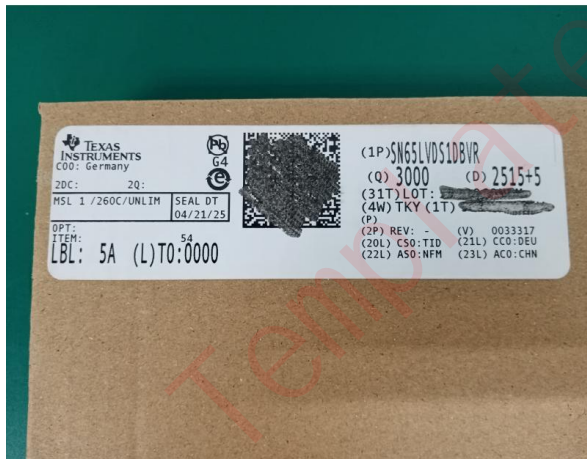
Received view-3



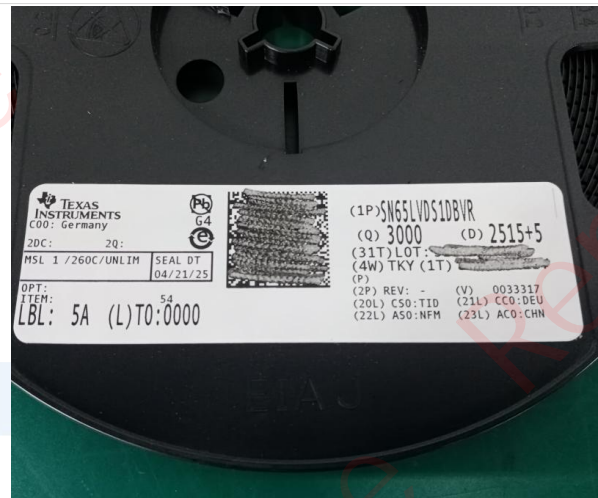
Received view-4



Received view-5



Received view-6



4. External visual inspection:

Applicable standard: **SAE AS6171/2A-2017**

Ambient temperature: $25 \pm 3\text{ }^{\circ}\text{C}$ Relative humidity: 45% ~ 65% RH

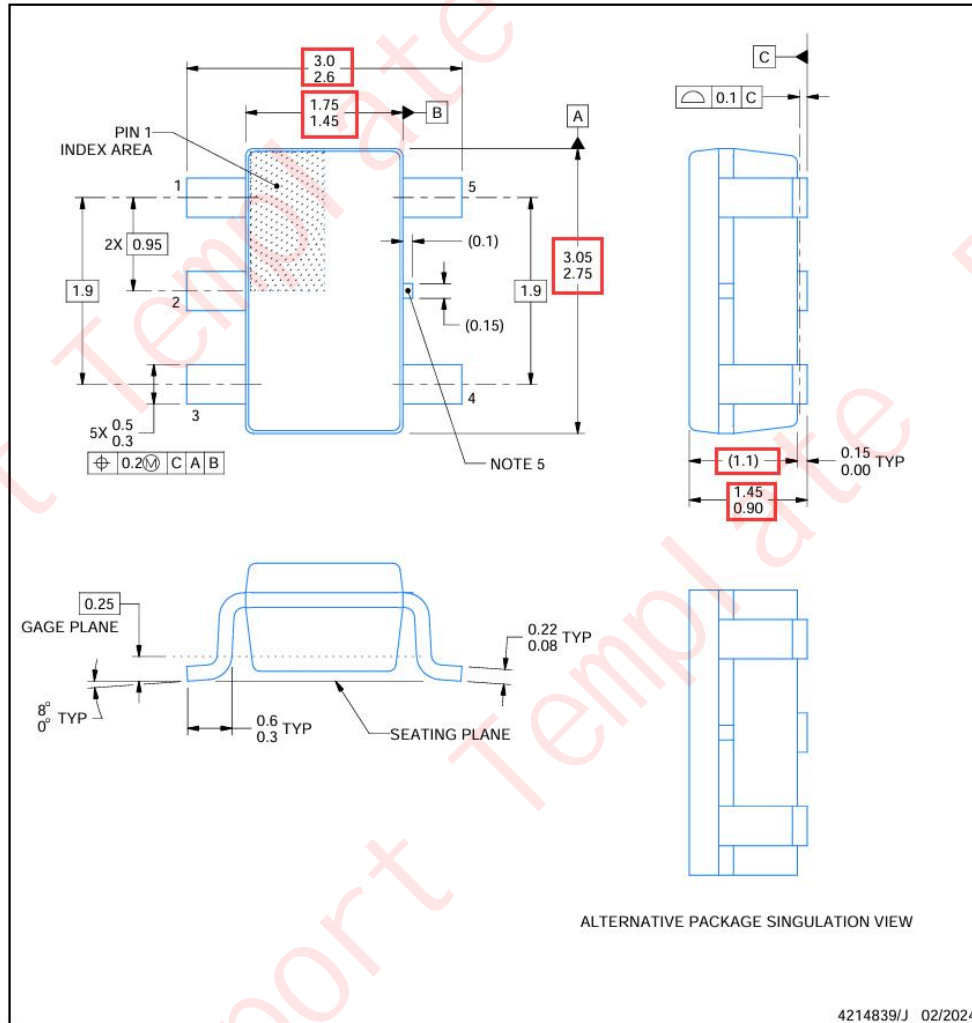
The customer provided 6000 PCS of **TI** Part Number **SN65LVDS1DBVR** for analysis and 10 pieces for External Visual Inspection (EVI). The details are as follows:

External visual inspection on 10 PCS samples. The surface silk screen of the devices was clear and complete, with no secondary coating, grinding, or damage marks. The leads were normal. One piece was randomly selected for size measurement, and the measured size parameters were within the standard range of the specification sheet. The 10 PCS samples passed the External visual inspection.

General EVI - 6000 PCS	Result	Exception Declaration
Parts are received in a single shipment	Acceptable	
Parts have multiple batches and/or code	Acceptable	
All parts are identical in appearance to the unaided eye (parts and packaging)	Acceptable	
Parts appear to have been subjected to the same handling, packaging, and/or storage conditions	Acceptable	
Parts have maintained their physical placement relative to each other	Acceptable	

Detailed EVI - 10 PCS	Result	Exception Declaration
Leads Test		
Are there any discoloration, dirt or residues on the Leads	Acceptable	
Are there any production marks on the Leads, Are there any exposed copper at the ends or other substrates	Acceptable	
Are the Leads missing, bent or not coplanar	Acceptable	
Scratches (or insertion marks) on the inner and/or outer surfaces of the Leads	Acceptable	
Whether the Leads are oxidized, corroded, have excessive or uneven coatings	Acceptable	
Hermetic devices and Marking Test		
Are the samples with the same date and batch number code marked differently	Acceptable	
Are there any visible previous marks or differences in the surface	Acceptable	
Hermetic devices differences, scratches or one-way wear, cracks, debris, etc	Acceptable	
Signs of residual substances on the surface, uneven discoloration or shadows, etc	Acceptable	
Signs of corrosion on the body of the part or exposed areas of the lead frame	Acceptable	
Blacktop, Mold indents filled or blacktopped	Acceptable	
Is the size of the hermetic devices consistent with the specification sheet	Acceptable	
Evidence of color fade on the body of the part	Acceptable	

Package dimensions



NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- This drawing is subject to change without notice.
- Reference JEDEC MO-178.
- Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25 mm per side.
- Support pin may differ or may not be present.

Parm	Unit	Datasheet	Value #1	Value #2	Value #3
L	mm	2.75 - 3.05	2.85	/	/
W1	mm	1.45 - 1.75	1.59	/	/
W2	mm	2.60 - 3.00	2.92	/	/
H1	mm	1.10 BSC	1.13	/	/
H2	mm	0.90 - 1.45	1.15	/	/

L



W1



W2



H1

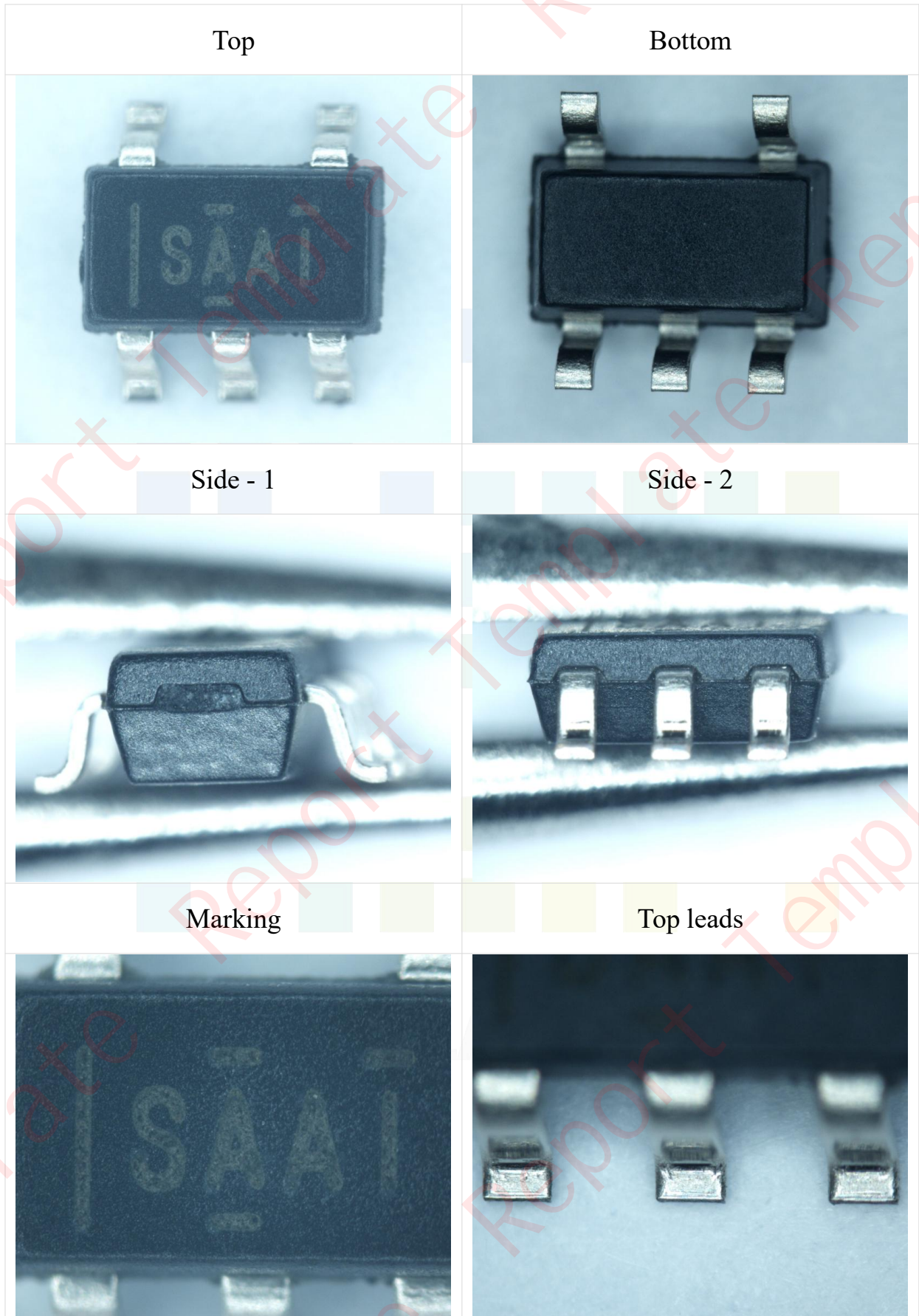


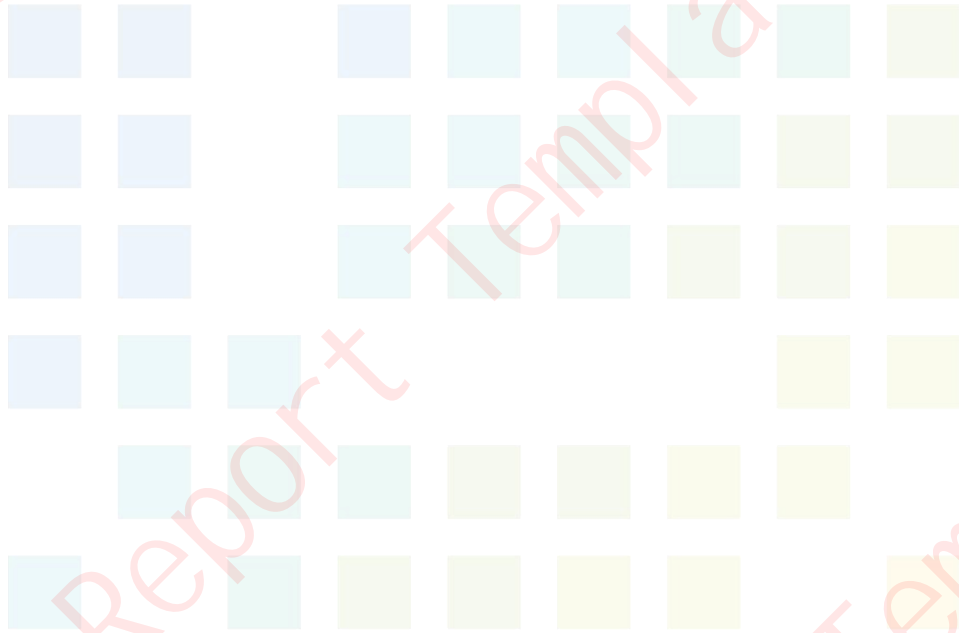
H2



Weight(g)







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5. Radiography(X-ray):

Applicable standard: **SAE AS6171/5-2022**


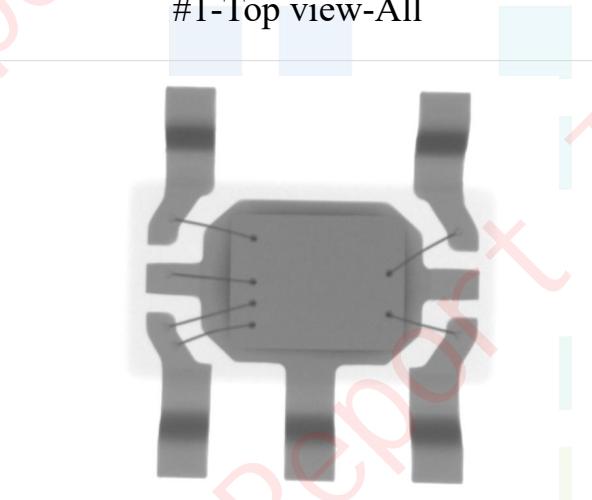

Ambient temperature: 25 ± 3 °C Relative humidity: 45% ~ 65% RH

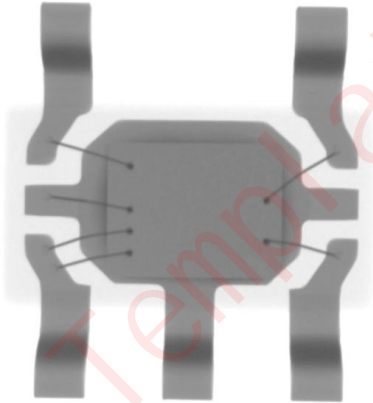
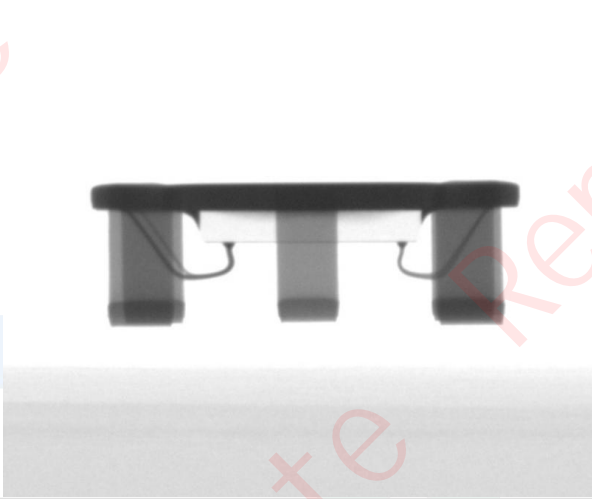
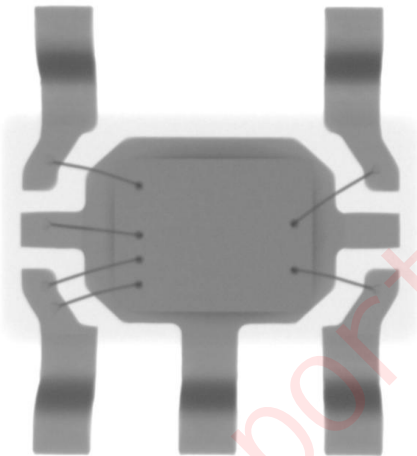
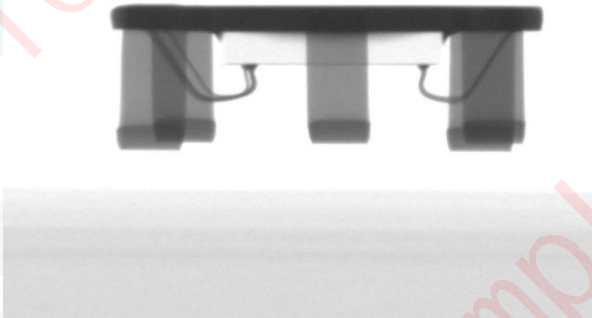
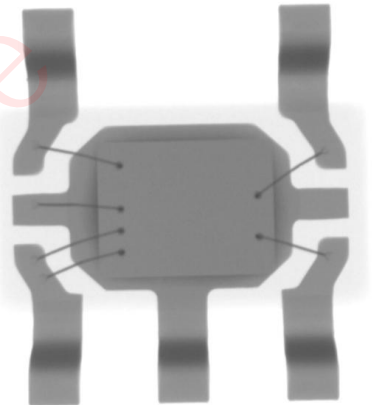
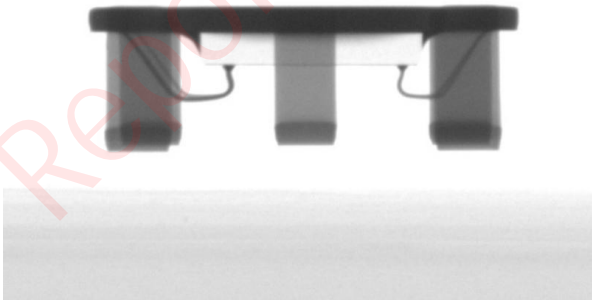
The customer provided 6000 PCS of **TI** Part Number **SN65LVDS1DBVR** for analysis and 5 pieces(#1-#5) for X-ray inspection. The details are as follows:

The 5 PCS samples were tested for X-ray inspection. 5 PCS samples have the same structure. No structure or bonding wire abnormal was found. The 5 PCS samples passed X-ray inspection.

Sample No	Test Items	Result
#1-#5	Whether there are cracks, bonding tilts, or anomalies outside the bonding range in the internal wafer	Acceptable
	Whether the internal bonding wire is broken, crossed wire, radian exceeding the standard, and solder joint is abnormal	Acceptable
	Check whether the internal lead rack and substrate structure are abnormal	Acceptable
	Whether the void at the internal bonding interface is abnormal. Whether the bonding material is separated from the main body, and the accumulation of the bonding material is too high	Acceptable
	Whether the internal wafer, bonding wire, bonding mode, material, lead frame, substrate structure and internal bonding are consistent when multiple samples are tested	Acceptable
	Side view inside the climbing height of the bonding material, the arc of the bonding wire, the distance between the bonding wire and the top, and the first and second solder joints are abnormal	Acceptable

	Whether there are attached or free particles in the sample exceeding 0.025mm, whether the material is metal	Acceptable
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Top	Bottom
	
#1-Top view-All	#1-Side view-All
	
#2-Top view-All	#2-Side view-All
	

<div>#3-Top view-All</div> 	<div>#3-Side view-All</div> 
<div>#4-Top view-All</div> 	<div>#4-Side view-All</div> 
<div>#5-Top view-All</div> 	<div>#5-Side view-All</div> 

6. Internal visual inspection:

Applicable standard: **SAE AS6171/4-2016**

Ambient temperature: 25 ± 3 °C Relative humidity: 45% ~ 65% RH

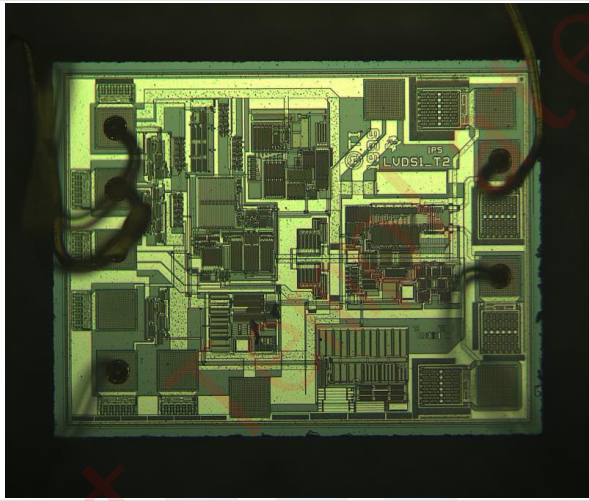
The customer provided 6000 PCS of **TI** Part Number **SN65LVDS1DBVR** for analysis and 1 piece for Internal visual inspection. The details are as follows:

Internal visual inspection was verified on 1 PCS sample. Manufacturer TI marking with 1999 copyright year and die marking LUDS1-T2 1P5 were found on the die surface, do not exhibit cracks or damage on die surface.

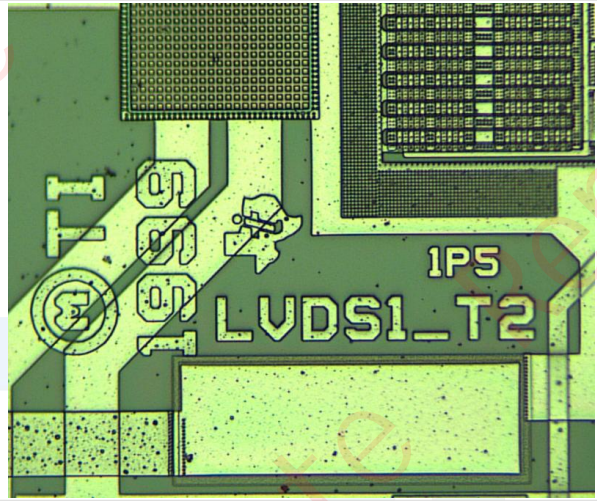
Devices confirmed to be the TI device.



Die topography



Die logo with marking and copyright



-End of Report-

Disclaimer

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2. The copy of the test report is invalid without the stamp of “company report seal” and “cross-page seal”.
3. The test report is invalid without the signatures of operator, supervisor and manager.
4. A modified or partial copy of the test report is invalid.
5. When there is disagreement with the test report, please submit the issue to us within 15 days from the date of receipt. Overdue information will not be accepted.
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